

Attendance:

Mr. Bernhard Laschinsky	Agere Systems
Mr. Bryan Kantack	Agilent Technologies, Inc.
Mr. Jesse Jaramillo	Amphenol
Mr. Mickey Felton	EMC
Mr. Mike Fitzpatrick	Fujitsu
Mr. Barry Olawsky	Hewlett Packard Co.
Mr. Rob Elliott	Hewlett Packard Co.
Mr. Dan Colegrove	HGST
Ms. Carrie Cox	IBM Corp.
Mr. George O. Penokie	IBM Corp.
Mr. Harvey Newman	Infineon Technologies
Mr. Schelto van Doorn	Intel Corp.
Dr. Mark Seidel	Intel Corp.
Mr. Pankaj Kumar	Intel Corp.
Mr. Michael Jenkins	LSI Logic Corp.
Mr. Gabriel Romero	LSI Logic Corp.
Mr. Keith Maloney	LSI Logic Corp.
Mr. John Lohmeyer	LSI Logic Corp.
Mr. Paul Wassenberg	Marvell Semiconductor, Inc.
Mr. Galen Fromm	Molex Inc.
Mr. Michael Rost	Molex Inc.
Mr. Tim Symons	PMC-Sierra
Mr. Rick Hernandez	PMC-Sierra
Mr. Alvin Cox	Seagate Technology
Mr. Allen Kramer	Seagate Technology
Mr. Benoit Mercier	STMicroelectronics
Mr. Stephen Finch	STMicroelectronics
Mr. Doug Loree	Toshiba
Mr. Kevin Witt	Vitesse Semiconductor
Mr. Larry McMillan	WDC

30 in attendance

Agenda:

1. Use of mode and pk-to-pk to measure de-emphasis.

Mode defined in 07-010r0

Reference proposals/documents:

<http://www.t10.org/ftp/t10/document.07/07-010r0.pdf>

<http://www.t10.org/ftp/t10/document.07/07-001r0.pdf>

<http://www.t10.org/ftp/t10/document.06/06-496r2.pdf>

Discussed the virtues of the mode measurement and there seems to be agreement on the methodology. At this point we are trying to define how to measure de-emphasis rather than to specify a specific value or range.

Mike Jenkins provided an initial picture of a new proposal on the measurement method with an actual signal using CJTPAT.

Concern that both positive and negative values need to be taken rather than just doubling one side.

The test pattern needs to be defined.

Mike to update 07-001 to include actual measurements and indication of how calculate with both positive and negative traces.

Kevin Witt to also update his proposal with a mode measurement rather than small window intervals.

Bryan Kantack and Alvin Cox to write a description of the mode value for the specification based on the decided-upon measurement method.

2. 1300mV versus 1200mV max pk-to-pk voltage spec. [Witt]

The 1300 mV proposal has been withdrawn after additional study.

3. Status on previous actions:

a. Barry will make some measurements to determine if the low frequency issues are being captured.

Next week.

b. Barry to propose a set of loss values for a zero length test load.

Next week.

c. Barry to find out whether the office environment is under Class A or Class B requirements.

<http://www.t10.org/ftp/t10/document.07/07-011r0.pdf>

This may be a question for STA.

Unclear as to whether a home-based business or office falls under class A or class B.

4. Review of Proposed 6G SAS Phy Specs for EMI Reduction [Jenkins]

<http://www.t10.org/ftp/t10/document.07/07-007r1.pdf>, and

<http://www.t10.org/ftp/t10/document.07/07-007r1.ppt>

Page 6: Smm table is not consistent with Annex D of the SAS speciation. Kevin Witt may have a table available for Mike to edit.

Page 7: Small changes in the skew value make a significant impact on the graph. The simplified model does not include coupling effects that reduce the skew. Actual skew is expected to be less due to tight coupling. Kevin, Mike, and Barry may share real data demonstrating this.

Page 8: The Vcm result is in error (off by a factor of 2).

Mike to update this document.

Next call 1/11/07.

Face-to-face 1/16/07.

Weekly teleconferences scheduled for Thursdays at 10 am CST:

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Webex information:

<https://seagate.webex.com/seagate>

Topic: SAS-2 PHY WG

Date: Thursday

Time: 10:00 am, Central Standard Time

Meeting number: 826 515 680

Meeting password: 6gbpsSAS